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Sommario/riassunto

Optical interferometry is used in communications, medical imaging, astronomy, and structural measurement. With the use of an interferometer engineers and scientists are able to complete surface inspections of micromachined surfaces and semiconductors. Medical technicians are able to give more concise diagnoses with the employ of interferometers in microscopy, spectroscopy, and coherent tomography.Originating from a one-day course, this material was expanded to serve as an introduction to the topic for engineers and scientists that have little optical knowledge but a need for more in the